

		The Ho	Attorney Docket No. SEL 142	<u>Seria</u> 09/43	1 No.			
	T OF PUBLICATION TED BY APPLICAN		<u>Applicant</u> Shunpei YAMAZAKI et al			·		
u	IED DI ALIMON		<u>Filing Date</u> November 8, 1999	<u>Group</u> 2811				
U.S. PATENT DOCUMENTS								
*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB- CLASS	FILING DATE		
Loke Loke	5,247,190 5,399,502 5,594,569 5,643,826 5,923,962	09/21/93 03/21/95 01/14/97 07/01/97 07/13/99	Friend et al Friend et al Konuma et al Ohtani et al Ohtani et al	257 437 349 437 438	40 1 122 88 150	04/18/90 05/05/93 07/20/94 10/25/94 04/28/95		
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	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB- CLASS	FILING DATE		
Loke	WO 90/13148	11/01/90 05/19/95	Cambridge Research and Innovation Ltd. Semiconductor Energy			04/18/90 10/29/93		
	JP 7-130652 JP 8-078329	03/22/96	Laboratory Co. Ltd. Semiconductor Energy Laboratory Co. Ltd.			09/05/94		
	JP 10-092576	04/10/98	Cambridge Display Technology Ltd.			04/18/97		
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22, 1998. English abstract re Japanese patent application no. 10-135469, published May 22, 1998.

English abstract re Japanese patent application no. 10-247735, published September 14, 1998.

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DATE CONSIDERED:

4/17/01

*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP form. Draw line through citation if not in conformance and not considered. Include a copy of this form with the next communication to applicant.

Substitute for form 1449B/PTO				Compl t if Known		(01p)
			1001 001105	Application Number	09/435,154	/
INFO	RMATIO	N D	ISCLOSURE	Filing Date	November 8, 1999	FFR
STATEMENT BY APPLICANT (use as many sheets as necessary)				First Named Inventor	Yamazaki	2001
				Group Art Unit	2811	1
				Examiner Name	S. Loke	Ve A
Sheet	3	of	3	Attorney Docket Number	SEL 142	MOEMARK

	OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS						
Examiner Initials	Cite No.1	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²				
Loke		U.S. Patent Application No. 09/432,662 (pending) to Yamazaki et al, filed November 8, 1999, including specification, claims, drawings and PTO filing receipt.					
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Examine	r	Date A. /. /					
Signature		Loke Date Considered 4/17/0/					

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¹ Unique citation designation number. ² Applicant is to place a check mark here if English language Translation is attached.